

The Dimension-3100 AFM is a robust instrument, capable of most functions expected from a modern atomic force microscope. The sample is attached to a motorized stage, while the cantilever is controlled by the piezoelectric drive.

### **Specifications**

|                    |   |
|--------------------|---|
| Modes of operation | Contact and tapping mode, force measurement       |
| Resolution         | Nanometer resolution possible, depending on probe |
| Control            | Highly automated, robust computer control         |
| Operation          | Keyboard, track ball and mouse                    |
| Display            | Dual screen for viewing multiple images/graphs    |
| Sample stage       | Motorized, 2 $\mu$ m resolution                   |
| Specimen area      | 120 mm x 100 mm                                   |
| Enclosure          | Heat insulating, vibration/sound damping          |
| Probes             | Accepts most Bruker AFM probes                    |